2017 89th ARFTG Microwave Measurement Conference (ARFTG 2017)

Honolulu, Hawaii, USA
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Session A: Communications I

Chair: Jon Martens, Anritsu

Thermal Transport in Transistors Based on GaN and Novel 2D Materials (Keynote)  N/A
Ali Shakouri, Purdue University,
West Lafayette, IN, USA

Independent Component Analysis for Multi-Carrier Transmission for 4G/5G Power Amplifiers  1
Praveen Jaruat1, Girish Chandra Tripathi1, Meenakshi Rawat1, Patrick Roblin2
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Qian Zhang, Wenhua Chen, Zhenghe Feng Department of Electronic Engineering, Tsinghua University, Beijing, China

Experimental Testbed for PA Characterization and Pre-Distortion with Relaxed Sampling Rate Requirements  9
Peter Bagot1, Souheil Ben Smida1, Oualid Hammi2
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Session B: Calibration

Chair: Dave Blackham, Keysight Technologies

G. Avolio1, D. F. Williams2, S. Streett2, M. Frey2, D. Schreurs1, A. Ferrero3, M. Dieudonne3
1KU Leuven, Belgium, 2NIST, Boulder, CO, USA, 3Keysight Technologies, CA, USA

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Ken Wong, Joe Gorin, Guoquan Lu
Keysight Technologies, Santa Rosa, CA

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C.-Y. Edward Tong1, Jake A. Connors2, Edward Garcia3 1Harvard-Smithsonian Center for Astrophysics, Cambridge, MA, USA, 2Harvard University, Physics Department, Cambridge, MA, USA, 3Noisewave Corporation, Whippany, NJ, USA.

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F.J. Schmückle1, T. Probst2, U. Arz2, G.N. Phung1, R. Doerner1, W. Heinrich1
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Session C: Communications II

Chair: Jeff Jargon, NIST

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Thomas M Wallis
NIST, Boulder, CO

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Keysight Technologies, Santa Rosa CA

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Karl Freiberger¹, Harald Enzinger¹, and Christian Vogel²
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²FH JOANNEUM – University of Applied Sciences, Austria

Session D: General Measurement

Chair: Andref Rumiantsev, MPI Corporation

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Zain Ahmed Khan¹,², Peter Händel², and Magnus Isaksson¹
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Czech Technical University in Prague, Prague, Czech Republic

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¹NPL, Teddington, UK, ²NIST, Boulder, CO, USA
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Keysight Technologies, Santa Rosa, CA

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Faculty of Electrical Engineering, Czech Technical University in Prague, Czech Republic

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National Metrology Institute of Japan, National Institute of Advanced Industrial Science and Technology, Japan

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National Institute of Standards and Technology, Boulder, CO, USA

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